

## **Manuel Fregolent – CV**

Manuel Fregolent is a post-doc researcher of the Department of Information Engineering of the University of Padova. He received the M.Sc. Degree in Electronic Engineering and the PhD in Information Engineering from the University of Padova, Italy in 2020 and 2024, respectively.

His research interests cover the characterization, physical modeling, and reliability of wide bandgap semiconductor devices, including vertical GaN devices and Ga<sub>2</sub>O<sub>3</sub>. In particular, he focused on the detection of deep levels in bulk material and on the analysis of charge trapping phenomena leading to threshold voltage instability.

He also spent a visiting period in Nagoya University (Japan), where he investigated the device processing and analysis of p-type GaN devices.